

Special Session

2020년 2월 13일(목), 10:45-12:15 / Room E (루비 II, 5층)

■ [TE2-SS] Beyond 7-nm Technology

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TE2-SS-1 10:45-11:00	파티클 오염으로 인한 극자외선 노광 기술용 펠리클의 열적 내구성 평가 Yong Ju Jang ¹ , Seong Ju Wi ² , Ha Neul Kim ² , and Jinho Ahn ^{1,2,3} <i>¹Division of Nanoscale Semiconductor Engineering, Hanyang University, ²Division of Materials Science and Engineering, Hanyang University, ³Institute of Nano Science and Technology, Hanyang University</i>
TE2-SS-2 11:00-11:15	Wafer-Scale, Conformal, and Low-Temperature Synthesis of Layered Tin Disulfides for Emerging Non-Planar and Flexible Electronics Jung Joon Pyeon ^{1,2} , In-Hwan Baek ^{1,3} , Woo Chul Lee ^{1,3} , Hansol Lee ⁴ , Sung Ok Won ⁴ , Ga-Yeon Lee ⁵ , Taek-Mo Chung ⁵ , Jeong Hwan Han ⁶ , Chong-Yun Kang ^{1,2} , and Seong Keun Kim ¹ <i>¹Center for Electronic Materials, KIST, ²KU-KIST Graduate School of Converging Science and Technology, Korea University, ³Department of Materials Science and Engineering and Inter-University Semiconductor Research Center, Seoul National University, ⁴Advanced Analysis Center, KIST, ⁵Division of Advanced Materials, KRICT, ⁶Department of Materials Science and Engineering, SEOULTECH</i>
TE2-SS-3 11:15-11:30	Machine-Learning-Based Device Optimization with TCAD Bokyeom Kim and Mincheol Shin <i>School of Electrical Engineering, KAIST</i>
TE2-SS-4 11:30-11:45	The Effect of Post Annealing for Atomic Layer Deposited P-type SnO Semiconductor Su-hwan Choi ¹ , Jung-hoon Lee ² , Hyun-jun Jeong ² , Seok-goo Jeong ¹ , and Jin-seong Park ^{1,2} <i>¹Division of Nanoscale of Semiconductor Engineering, Hanyang University, ²Division of Materials Science and Engineering, Hanyang University</i>
TE2-SS-5 11:45-12:00	Sub-μA and 3-bit per Cell Operation of Self-rectifying Resistive Memory in a 1 Mb Crossbar Array Device Kanghyeok Jeon ^{1,2} , Jin Joo Ryu ¹ , Doo Seok Jeong ² , Min Kyu Yang ³ , and Gun Hwan Kim ¹ <i>¹Division of Advanced Materials, KRICT, ²Division of Materials Science and Engineering, Hanyang University, ³Department of Computer Car Mechatronics, Sahmyook University</i>
TE2-SS-6 12:00-12:15	Improved Measurement Accuracy with TSOM Image Registration at Sub-Pixel Level Junhee Jeong, Youngmin Park, and Joonghwee Cho <i>Department of Embedded Systems Engineering, Incheon National University</i>